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Recent Advances in Deep Learning for Image Analysis

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Message from the Guest Editors

Dear Colleagues,

Recently, deep learning algorithms have been used for a wide range of computer vision and image analysis tasks. However, deep learning still poses some challenges in regard to training time, network size, accuracy, computing power, and overfitting. These challenges need to be addressed in order to provide reliable and efficient deep learning networks. Hence, the aim of this Special Issue is to cover novel, optimized, high-performance, and hybrid deep-learning-based approaches for image analysis to address the aforementioned challenges in a variety of applications. Topics of interest include, but are not limited to, the following:

- Deep-learning-based image analysis in various disciplines.
- Image analysis using deep learning.
- Effective augmentation methods for deep-learning-based image analysis.
- Hybrid machine learning and deep learning methods for image analysis.
- Efficient deep learning architectures for image analysis.
- Deep learning models on mobile and embedded devices for image analysis.
- Transfer learning, domain adaptation, and knowledge distillation for image analysis.



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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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